

## **IEC QUALITY ASSESSMENT SYSTEM (IECQ)**

covering Electronic Components, Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

## Schedule of Scope to Certificate of Approval

**Independent Testing Laboratory** 

IECQ Certificate No.: IECQ-L ULTW 17.0001-01
CB Certificate No.: 50600165 ITL

Schedule Number: IECQ-L ULTW 17.0001-01-S Rev No.: 6 Revision Date: 2024/02/10 Page 1 of 1

## Appendix-1 (50600165 ITL) Schedule of Scope to Certificate of Approval

Test Items	Standard/Method
I-V Probe station	WI-LM-0120
InGaAs microscope/Optical Beam Induced Resistance Change (OBIRCH)	WI-LM-0121
SAT (Scanning Acoustic Tomography).	WI-LM-0333
3D X-ray	WI-LM-0324
Dual-Beam Focused Ion Beam(DB-FIB)	WI-LM-0369
Reactive Ion Etching(RIE)	WI-LM-0306
Backside Polisher	WI-LM-0307
3D Optical Microscope	WI-LM-0359
Scanning Electron Microscope(SEM)	WI-LM-0362/ WI-LM-0302
Laser decap	WI-LM-0363

Technical Reviewer of DQS:\_\_\_\_\_\_ Date: 02/10/2024

